

204-425

PATENT NUMBER and ISSUE DATE

## U.S. UTILITY Patent Application

A N	<b>APPL NUM</b> 10050417	<b>FILING DATE</b> 01/16/2002	CLASS	SUBCLASS EHT	GAU 2812	EXAMINER (Company)			
	**APPLICANTS: Phan Khoi, Ernardt Jeffrey. Cheng Jerry, Bartlett Richard. Coniglio Anthony, Grundke Wolfram, Bradway Carol. Sutton Daniei, Mazur Martin.								
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	**CONTINUING DATA VERIFIED: THIS APPLIN CLAIMS BENEFIT OF 60/285.197 04/20/2001								
	** FOREIGN APPLICATIONS VERIFIED:								
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	Foreign priority clair 35 USC 119 condit	ned	yes نـ	<b>∟</b> no		ATTORNEY DOCKET NO G0131			
j.	FITLE: Methodi Jevice manufact	s and systems for d luring process	controlling	g resist residue	e defect	s at gate layer in a semiconductor			
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NOTICE OF ALL	DWANCE MAILED		CLAIMS ALLOWED				
		Assistant Examiner	Total Claims		Print Claim for O.G		
ISS	UE FEE		DRAWING				
Amount Due	Date Paid		Sheets Drwg.	Figs.Drwg	Print Fig.		
		Primary Examiner	,				
TERMINAL		PREPARED FOR ISSUE	Application Examiner				
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